

**AMENDMENTS TO THE ABSTRACT**

***Please replace the Abstract of the Disclosure with the following Replacement Abstract:***

A measuring device and measuring method are provided for testing the cut quality of a sheet. The measuring device is provided with a transparent scanning substrate for holding the sheet, a scanning device with a scanning window, and a cover for covering the sheet held by the scanning substrate, wherein the scanning window overlaps the sheet, forming edge regions, and the cover has different reflection properties from the sheet for producing a high-contrast scanned image of the sheet and of the edge regions between the sheet and the scanning window. The measuring method includes positioning the sheet on a transparent scanning substrate, covering the sheet with a cover, and scanning the sheet with a scanning device, wherein the scanning device scans in the region of a scanning window which encompasses both the sheet and edge regions surrounding the sheet, and differences in contrast between the sheet and the edge regions are detected.